DEC 0 4 2003

Attorney's Docket No.: 04873-074002

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Dvorkis et al.

Art Unit: 2876

Serial No.: 10/050,625

Examiner: Frech, Karl D.

Filed

: January 16, 2002

Title

: OPTICAL SCANNER WITH SEGMENTED COLLECTION MIRROR

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Applicants submit the references listed on the attached form PTO-1449. Applicants do not concede that the listed references are prior art.

This statement is being filed after a first Office action on the merits, but before receipt of a final Office action or a Notice of Allowance. A check for \$180 in payment of the late submission fee of §1.17(p) is enclosed. Please apply any other charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

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DEC 0 4 2003 Substitute form PTO-1449 (Modified in

U.S. Department of Commerce Patent and Trademark Office

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Application No. 10/050,625

Informati n Disclosure Statement by Applicant (Use several sheets if necessary)

Applicant Dvorkis et al.

Group Art Unit 2876

(37 CFR §1.98(b))

Filing Date January 16, 2002

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	6575368	06/10/03	Tamburrini et al.			
	AB	5149949	09/22/92	Wike, Jr.		*	
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK					-	

Foreign Patent Documents or Published Foreign Patent Applications							
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	slation No
	AL						
	AM						
	AN						
	AO			•		_	
	AP						

Other Documents (include Author, Title, Date, and Place of Publication)					
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EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.			